

High Power GaN Transistors

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Integra Technologies, Inc.



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SCOPE

- $>100\text{W}$
- $>1\text{GHz}$
- Pulsed





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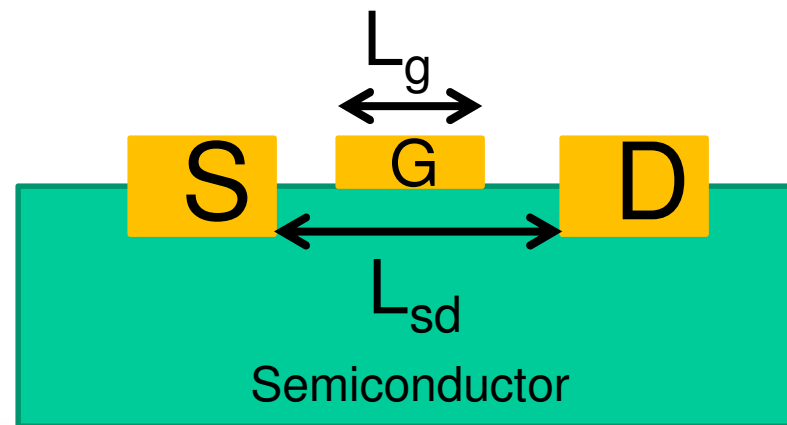
AGENDA

- Technical Background
- Integra Die Manufacturing Process
- State-of-the-art GaN Products
- Conclusions





THE TECHNICAL PROBLEM



As frequency \uparrow

$L_g \downarrow$ (to reduce capacitance)

$L_{ds} \downarrow$ (to reduce parasitic series resistance)

$V_{dsBK} \downarrow$ (Critical field remains constant)

RF output power /mm of gate width \downarrow

The solution: Use a semiconductor with as high a critical field as possible



THE TECHNICAL PROBLEM (Cont.)

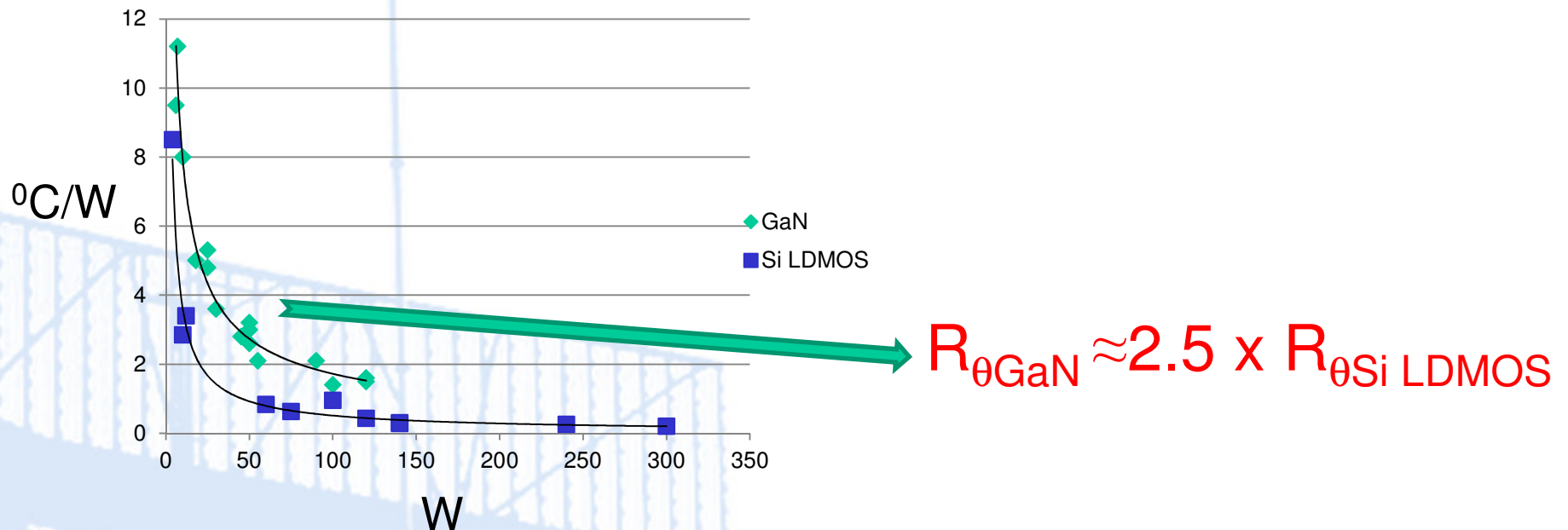
	Critical Field	Thermal Conductivity
Si	x	y
GaN	10x	y
SiC	10x	3y

- Cannot utilise factor of 10 power advantage of GaN c.f. Si using only GaN because of thermal limitation
- Even GaN on SiC will allow only a factor of 2-3 power advantage in CW
- GaN on SiC can offer >3x Si power in pulsed applications
- NB Higher power/mm² means lower Capacitance/Watt i.e. GaN can operate to higher frequency than Si.



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CW Thermal resistance of discrete single-ended transistors

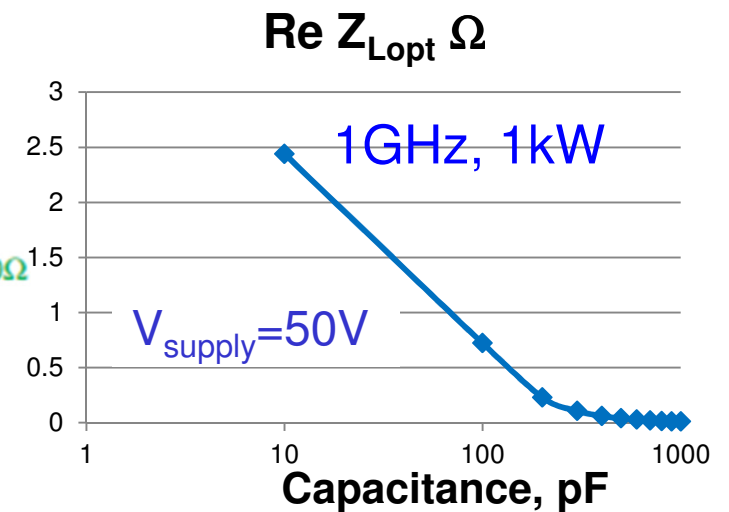
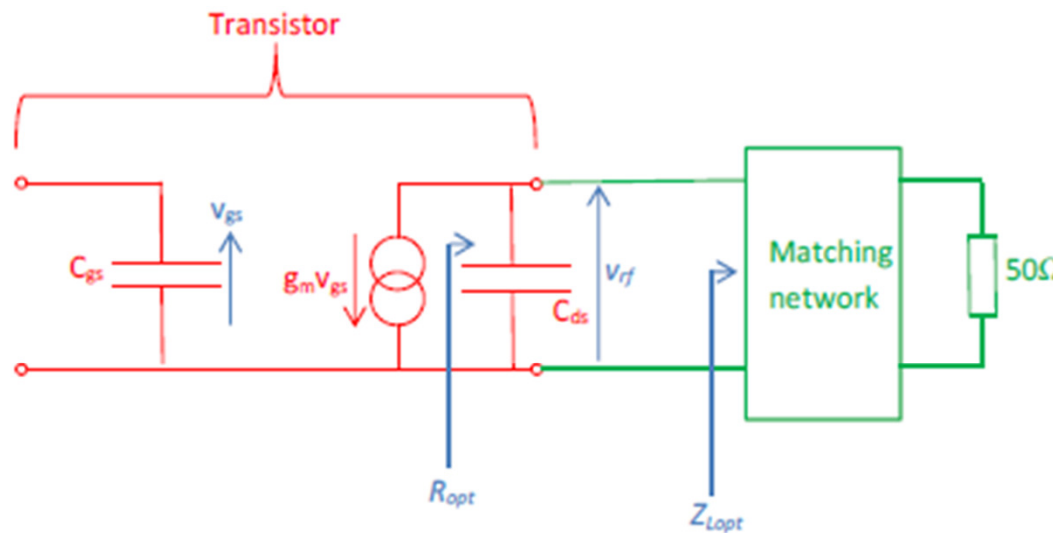


GaN is an ideal technology for pulsed applications!

16 manufacturers worldwide of pulsed GaN transistors!



IMPORTANCE OF LOW CAPACITANCE



$$\blacksquare Z_{Lopt} = \frac{R_{opt}}{1 - j\omega C_{ds} R_{opt}}$$



TECHNOLOGY COMPARISON

Si Bipolar

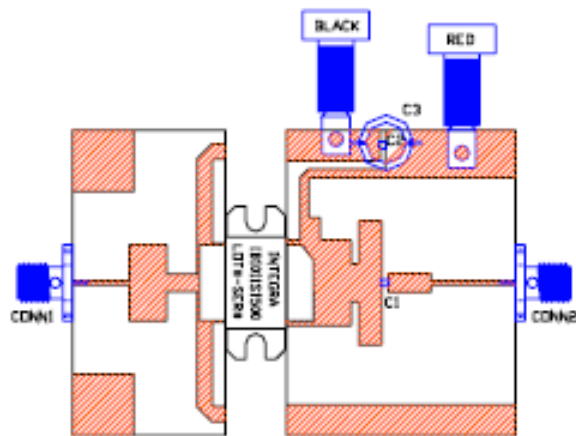
- Very mature
- Very reliable
- Higher efficiency than LDMOS (class C vs class A/B) – almost as good as GaN
- Simplest & cheapest circuits of any technology
- Frequency extension via common-base mode
- Lowest gain
- Very non-linear
- BeO package



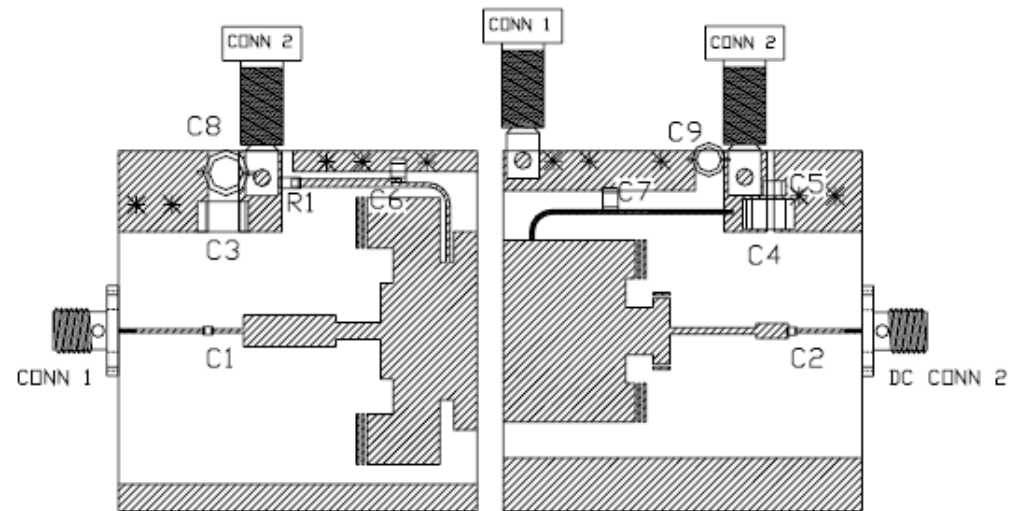
TECHNOLOGY COMPARISON

Si Bipolar

- Simplest & cheapest circuits of any technology



1.5kW bipolar L band
Just 2 chip capacitors
1 supply voltage



1kW LDMOS L band
10 capacitors, 1 resistor
2 supply voltages



TECHNOLOGY COMPARISON

Si Bipolar

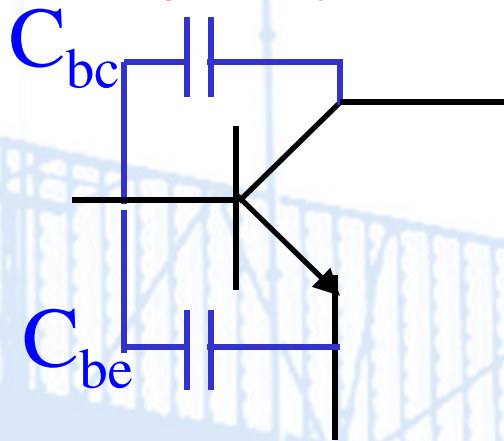
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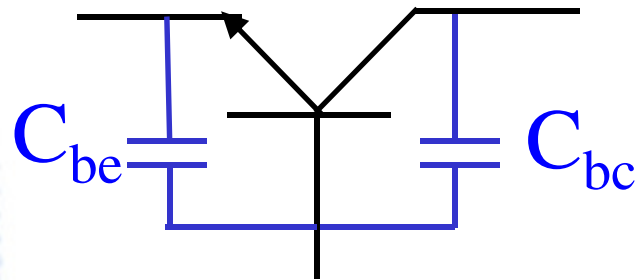
TECHNOLOGY COMPARISON

Si Bipolar

- Frequency extension via common-base mode



$$f_t \propto \frac{1}{C_{in}} = \frac{1}{C_{be} + C_{bc}}$$



$$f_t \propto \frac{1}{C_{in}} = \frac{1}{C_{be}}$$

FETs have C_{ds} which is comparable in value to C_{gs} so no frequency extension by using common gate mode



TECHNOLOGY COMPARISON

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TECHNOLOGY COMPARISON

Si LDMOS

- Very linear
- BeO-free and cheaper package
- About 2dB more gain than bipolar but less than GaN
- Lowest efficiency
- No increase in power output compared with bipolar



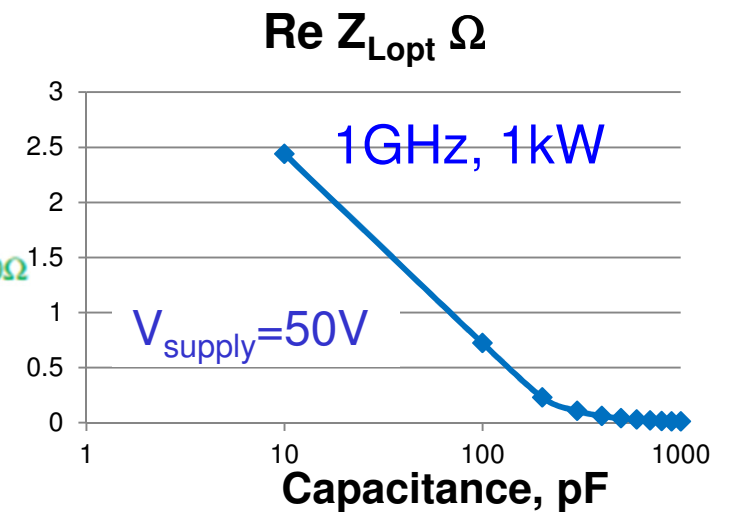
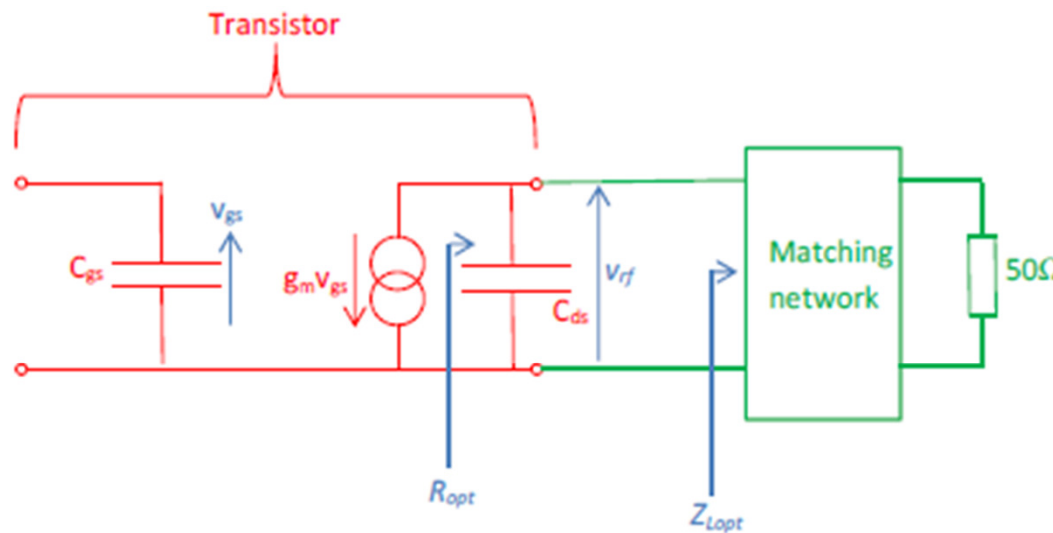
TECHNOLOGY COMPARISON

GaN

- Lowest capacitance per Watt of any technology
 - Wider bandwidth and higher frequency, less ripple
- Higher optimum load impedance
- Highest power density
 - Thermal issues
- Worse linearity than LDMOS



IMPORTANCE OF LOW CAPACITANCE



$$\blacksquare Z_{Lopt} = \frac{R_{opt}}{1 - j\omega C_{ds} R_{opt}}$$



TECHNOLOGY COMPARISON

2.7-2.9GHz, 300μs, 10% duty cycle

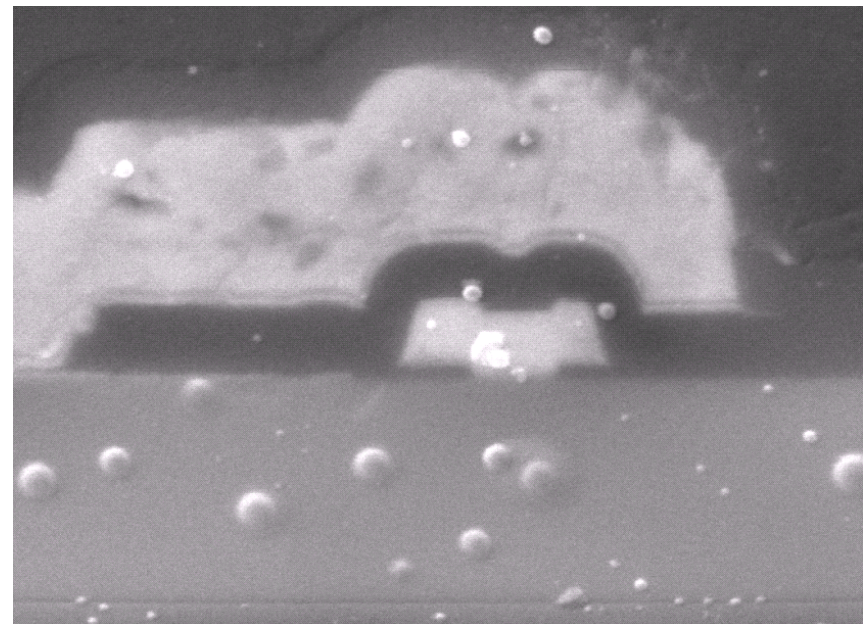
Device					
	Technology	Power (W)	Power-Added Efficiency %	Gain (dB)	Voltage (V)
IB2729M170	Si Bipolar	190	45	9.5	36
ILD2731M140	LDMOS	180	40.5	10.5	32
IGN2729M250	GaN	260	51	9.5	36
IGN2729M800	GaN	1000	55	11	50



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Integra Die Manufacturing Process

- Integra designs and manufactures its own GaN die
- Die specifically designed for **pulsed operation**
- 4" GaN on SiC (6" ready)
- 0.5 μ m process
- Ti/Al/Ni/Au Ohmic contacts
- Ni/Au Gate contact
- 3 mil die thickness
- Double field plate design
- No via holes
- All gold process for high reliability
- High breakdown voltage for reliable 50V operation

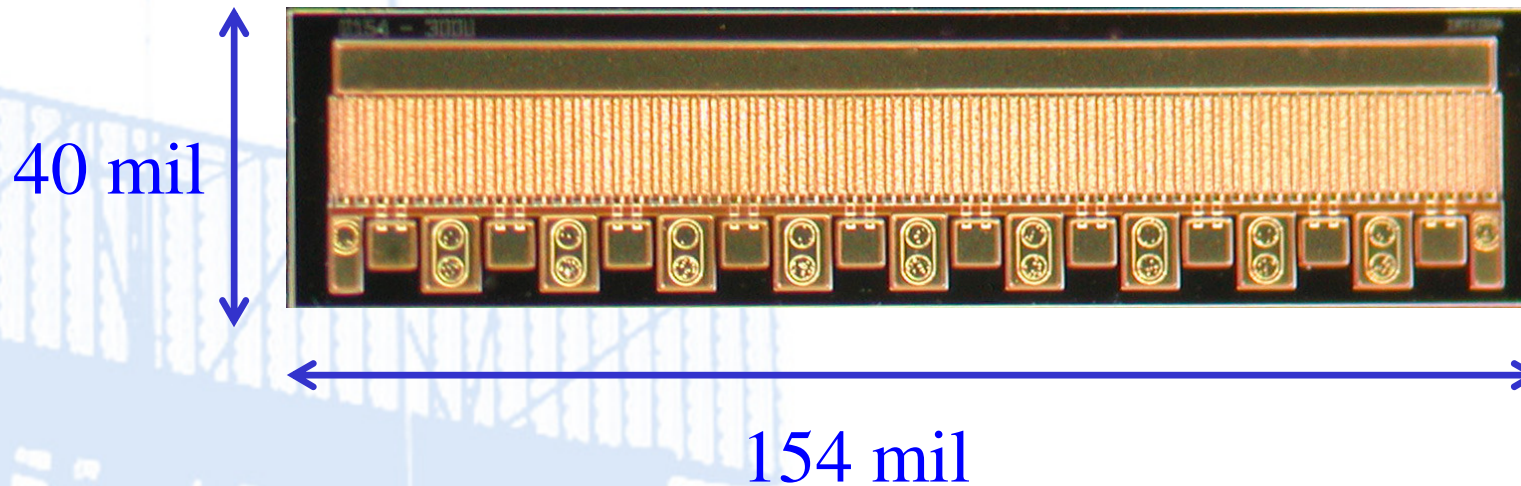




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Die Details

- 36mm total gate periphery
- 300 μ m finger width
- >150W 2.7-2.9GHz





AGENDA

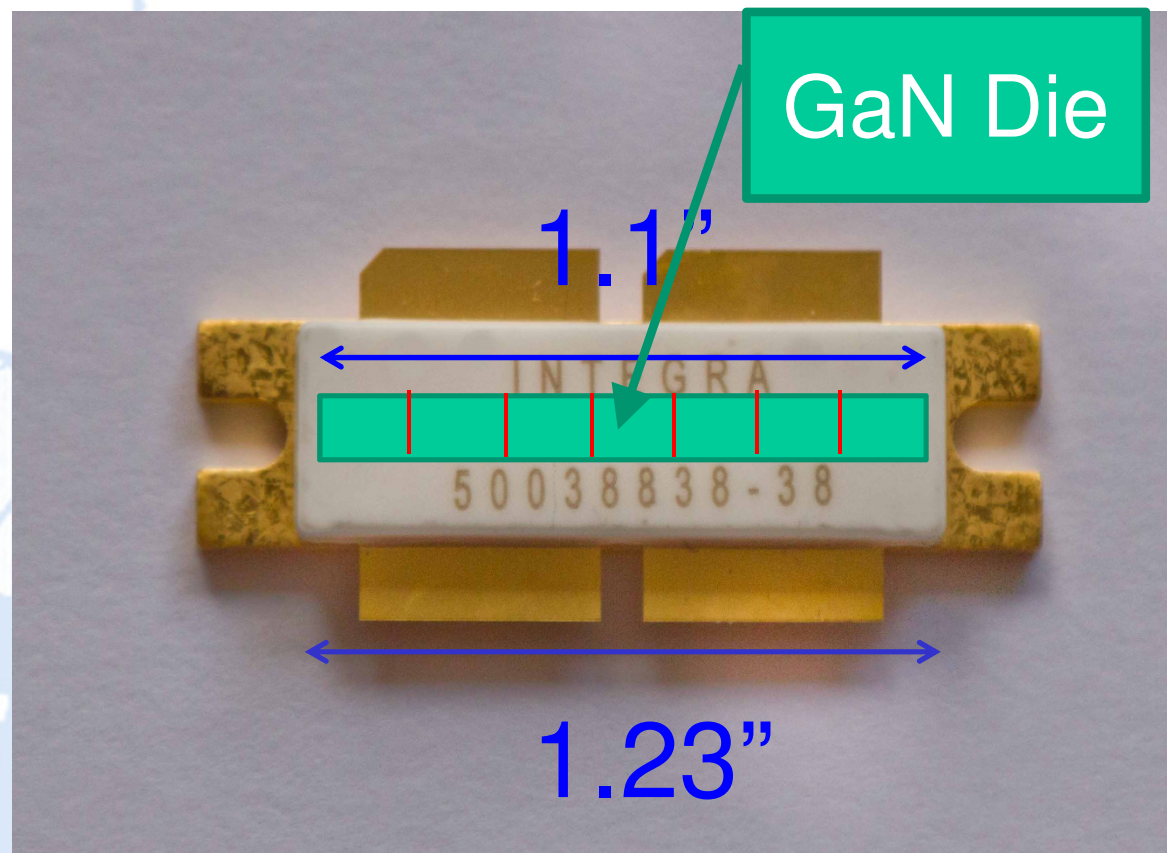
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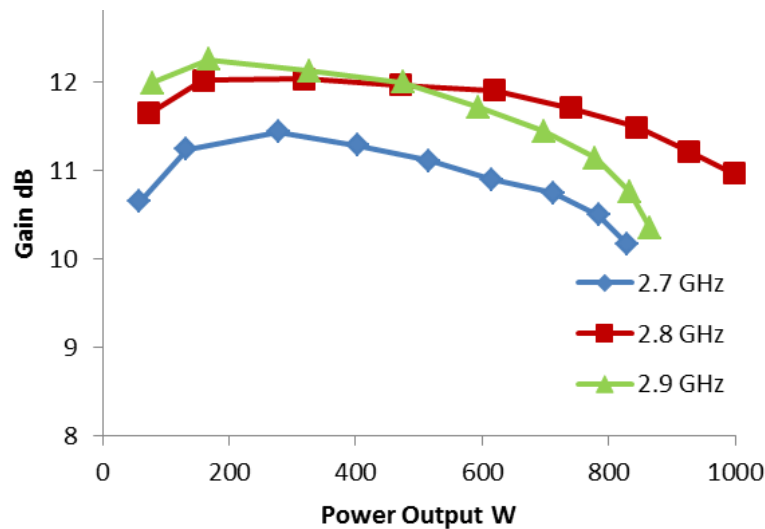
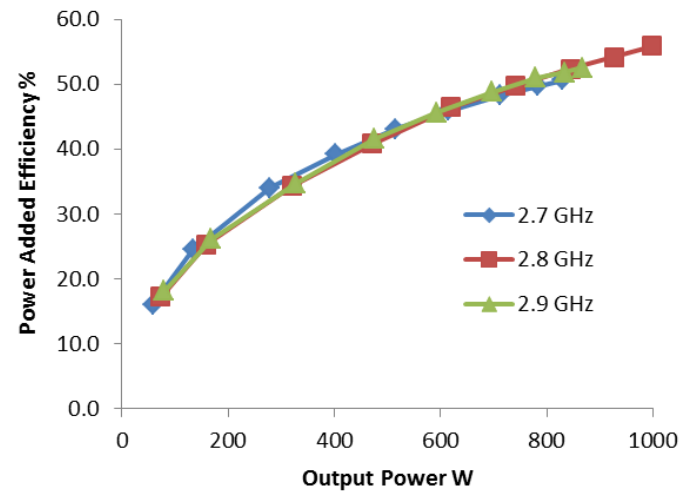
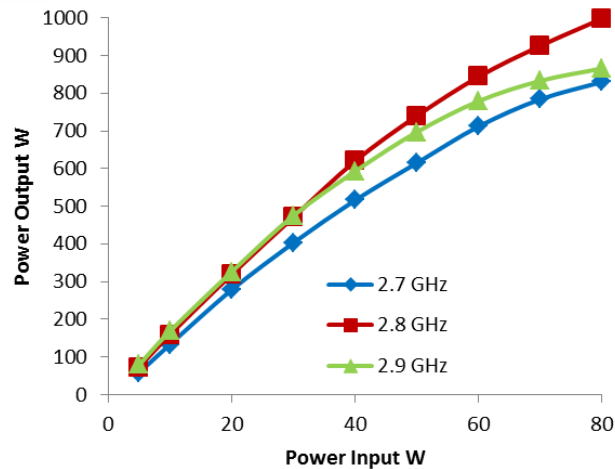
Integra 800W S band Package Details





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Integra 800W S band Results



Test Conditions:
300 μ s, 10%
50V, I_{DQ} = 100mA



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Integra 135W 3.1-3.5GHz 50Ω matched transistor



Test Conditions:
300μs, 10%
46V, $I_{DQ} = 25\text{mA}$

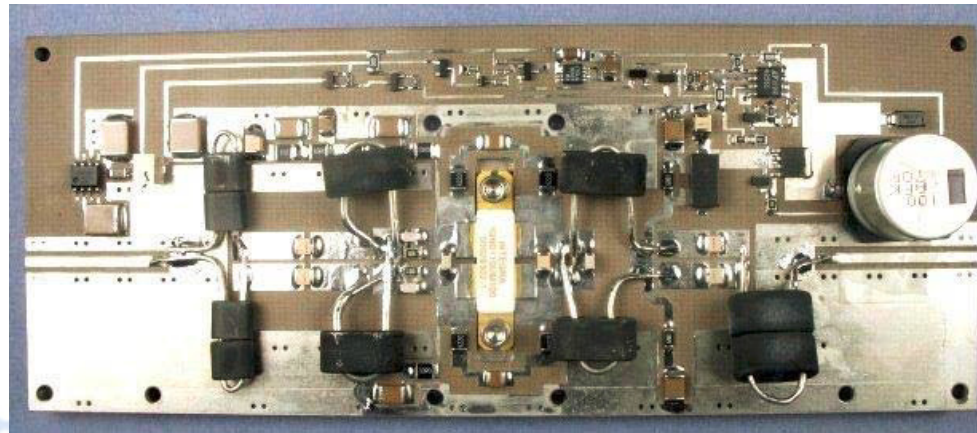
Typically 13dB gain, 50% efficiency, 10dB return loss

Typical application: phased array radar

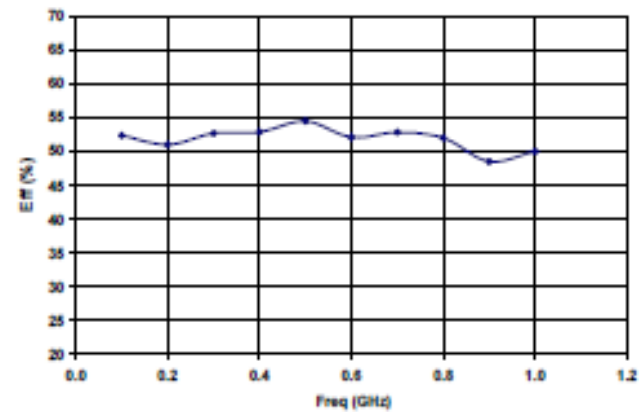
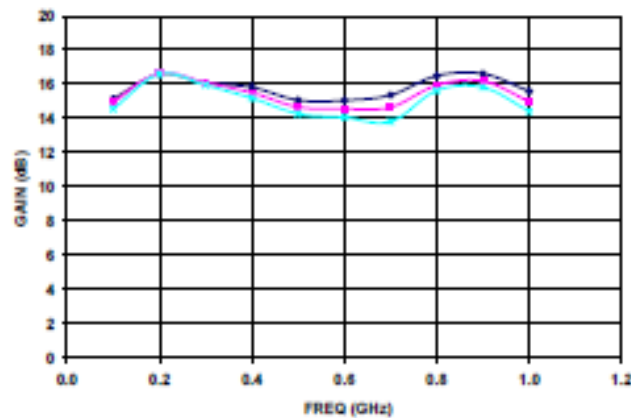


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100W CW 100-1000MHz GaN Pallet



Test Conditions:
 $V_{ds}=28V$
 $I_{DQ}=480mA$



Exploits low pF/W advantage of GaN



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CONCLUSIONS

This paper has shown examples of state-of-the-art GaN products

